#### DIALS: DIFFRACTION INTEGRATION FOR ADVANCED LIGHT SOURCES

HDRMX 4 LUND MARCH 2017 GRAEME WINTER DIAMOND LIGHT SOURCE



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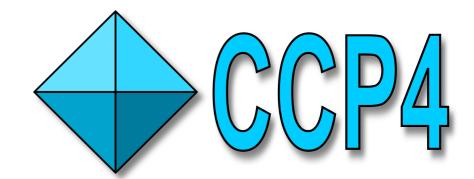
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#### PROJECT SUPPORT

Diffraction Integration for Advanced Light Sources







EU FP7: #283570 NIH: GM095887 & GM102520 WT: 202933

#### OPEN SOURCE

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#### CORE DEVELOPMENT TEAMS

- DIALS East: PI Gwyndaf Evans; David Waterman, Richard Gildea, James Parkhurst, Markus Gerstel, Luis Fuentes Montero, Graeme Winter - synchrotron rotation data + 2 shortly
- DIALS West: PI Nick Sauter; Aaron Brewster, Iris Young
   X-FEL serial crystallography

#### ACKNOWLEDGEMENTS

	re	esearch papers							
Acta Crystallographica Section D	XDS		research papers						
Biological Crystallography ISSN 0907-4449	AD3		Acta Crystallographica Section D Biological Crystallography	The integration of macromolecular diffraction data					
Wolfgang Kabsch	The usage and control of recent modifications of the program package XDS for the processing of rotation images are	Received 19 August 2009 Accepted 9 November 2009	ISSN 0907-4449						
Max-Planck-Institut für Medizinische Forschung, Abteilung Biophysik, Jahnstrasse 29, 69120 Heidelberg, Germany	described in the context of previous versions. New features include automatic determination of spot size and reflecting range and recognition and assignment of crystal symmetry. Moreover, the limitations of earlier package versions on the number of correction/scaling factors and the representation of	A version of this paper will be published as a chapter in the new edition of Volume F of International Tables for	Andrew G. W. Leslie	The objective of any modern data-processing program is to produce from a set of diffraction images a set of indices ( <i>hkls</i> ) Received 19 May 2005 Accepted 24 November 2005					
Correspondence e-mail: wolfgang.kabsch@mpimf-heidelberg.mpg.de	pixel contents have been removed. Large program parts have been restructured for parallel processing so that the quality and completeness of collected data can be assessed soon after measurement.	Crystallography.	MRC Laboratory of Molecular Biology, Hills Road, Cambridge CB2 2QH, England	with their associated intensities (and estimates of their uncertainties), together with an accurate estimate of the crystal unit-cell parameters. This procedure should not only be reliable, but should involve an absolute minimum of user					
	1. Functional specification		Correspondence e-mail: andrew@mrc-lmb.cam.ac.uk	intervention. The process can be conveniently divided into three stages. The first (autoindexing) determines the unit-cell parameters and the orientation of the crystal. The unit-cell					

#### research papers

Acta Crystallographica Section D Biological Crystallography ISSN 0907-4449

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#### The finer things in X-ray diffraction data collection

X-ray diffraction images from two-dimensional position-

sensitive detectors can be characterized as thick or thin, depending on whether the rotation-angle increment per image

is greater than or less than the crystal mosaicity, respectively.

The expectations and consequences of the processing of thick and thin images in terms of spatial overlap, saturated pixels,

X-ray background and  $I/\sigma(I)$  are discussed. The d\*TREK

software suite for processing diffraction images is briefly introduced, and results from d\*TREK are compared with

Two-dimensional position-sensitive detectors have been used for many years in X-ray diffraction data collection. In particular, data from crystals of macromolecules such as proteins, oligonucleotides and their complexes are almost always

acquired with an area detector such as film (now virtually obsolete), a multi-wire system, an imaging plate or the recently commercialized charge-coupled device (CCD)

coupled to a phosphor-coated fiber-optic taper. With all these detectors, the crystal, centered in the X-ray beam, is rotated or oscillated around a single axis through a small angle of 0.1 to

~2.0°, while counts from diffracted photons are accumulated for a specified time. At the end of the small rotation, the detector is read out and the counts are stored as an image: a

two-dimensional array with each array element (pixel) related to a distinct position on the detector and the number of

those from another popular package.

1. Introduction

Received 6 May 1999 Accepted 5 July 1999

#### Laboratoire pour l'Utilisation du Rayonnement Electromagnétique

#### Proceedings

parameters may indicate the likely Laue group of the crystal. The second step is to refine the initial estimate of the unit-cell

Centre National de la Recherche Scientifique

Université Paris-Sud

of the EEC Cooperative Workshop

on Position-Sensitive Detector Software

(Phases I & II)

#### WHAT IS DIALS?

- Indexing, refinement and integration programs
- Scope similar to MOSFLM i.e. does not include scaling use POINTLESS/AIMLESS for scaling (work in progress)
- Integration algorithm similar to XDS
- Does not currently include a GUI (in development) though does include a range of visual analysis tools
- Also DIALS is a toolkit, so you can do lots more

#### PHILOSOPHY

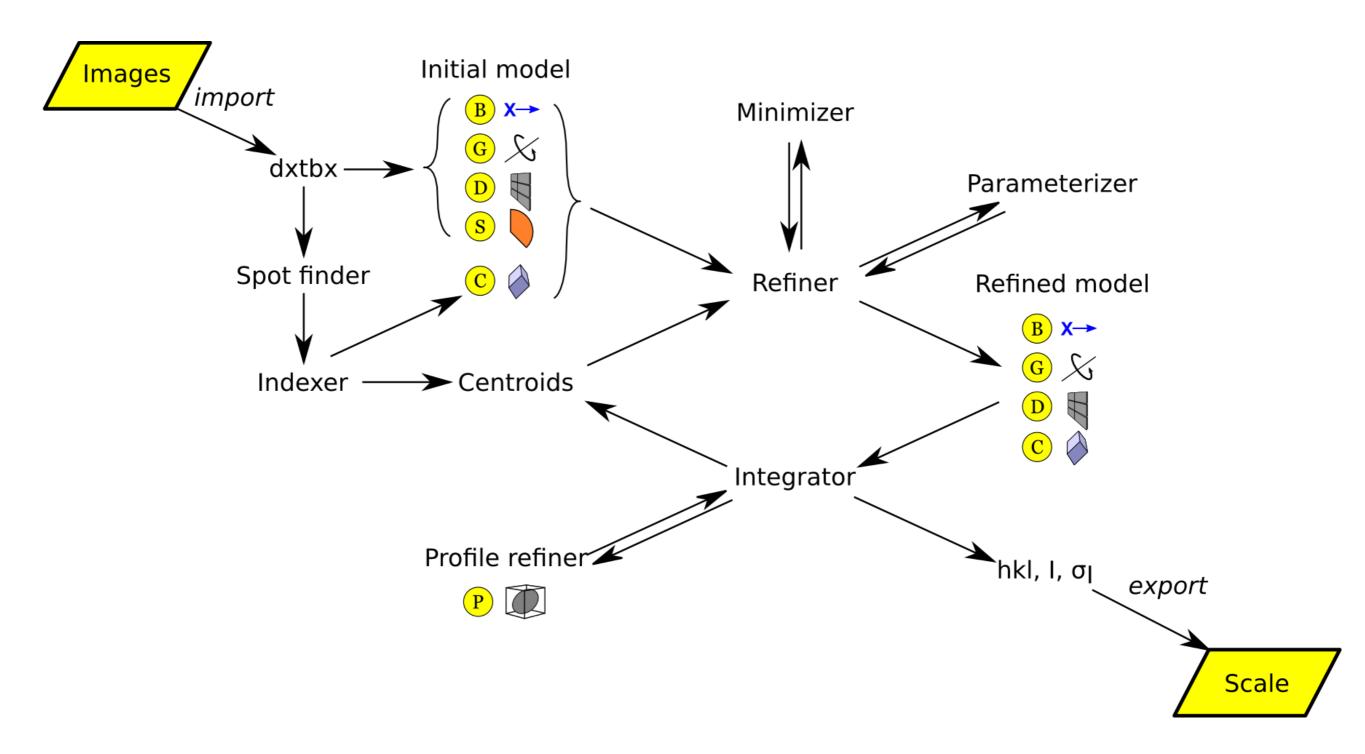
- Global analysis and model take data from every image in your data set
- No assumptions made about experimental geometry completely general / vectorial description
- Treat data as 3D volume not 2D "frames"
- Toolkit for data processing but you can do fun experiments with a little code

# WORKFLOW

- IMPORT
- FIND SPOTS
- NDEX → SELECT LATTICE
- REFINE REINDEX
- INTEGRATE
- EXPORT MTZ
- POINTLESS\*

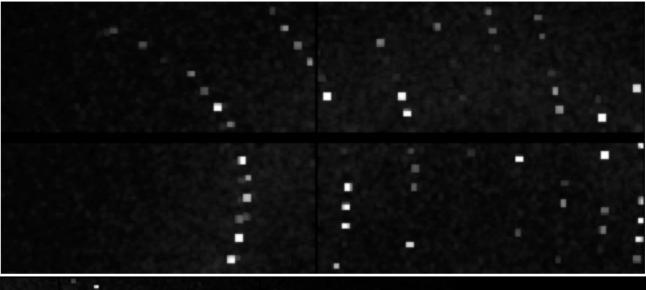
- import read headers, construct model of experiment
- find\_spots find spots on every image; 3D if rotation data
- index index the reflection list (may be > 1 sweep) in P1 & perform static refinement
- refine\_bravais\_settings consider / refine indexed spots in all possible lattices
- reindex reindex the indexed spot list
- refine actually refine the model, usually with scan varying model
- integrate actually integrate the data
- export\_mtz export an MTZ file for scaling with pointless & aimless (CCP4)

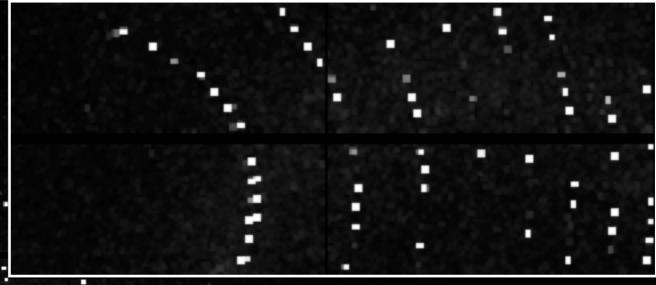
#### DIALS

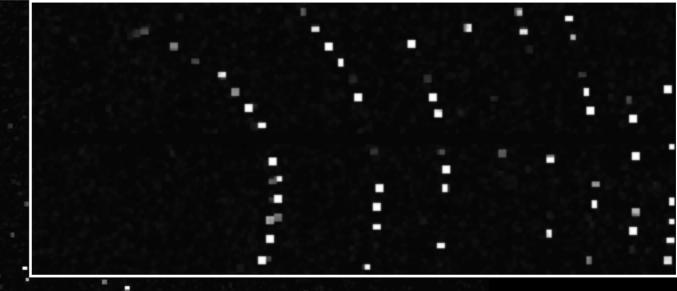


# ALGORITHMS







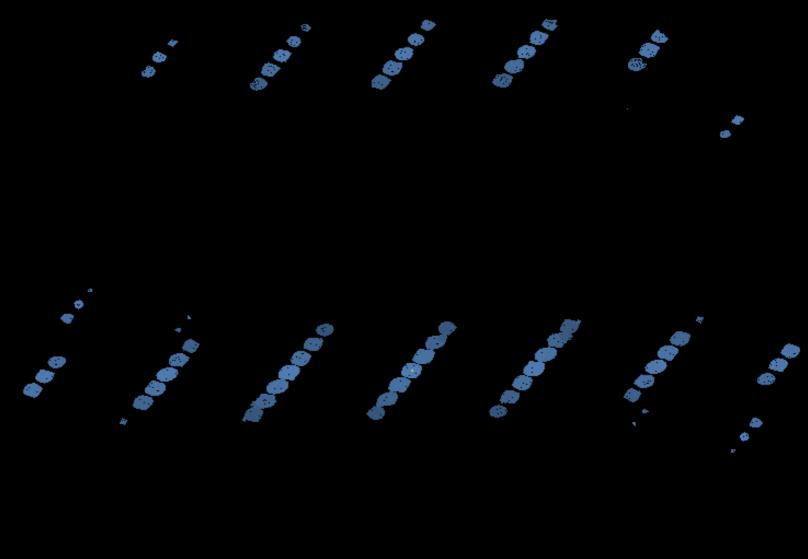


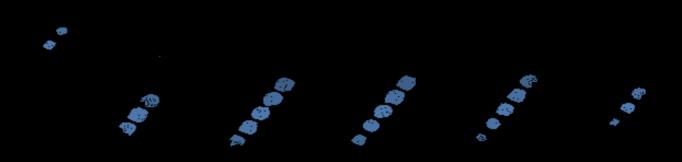
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#### INDEXING

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#### INDEXING





#### INDEXING

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#### SOLUTION PICKING

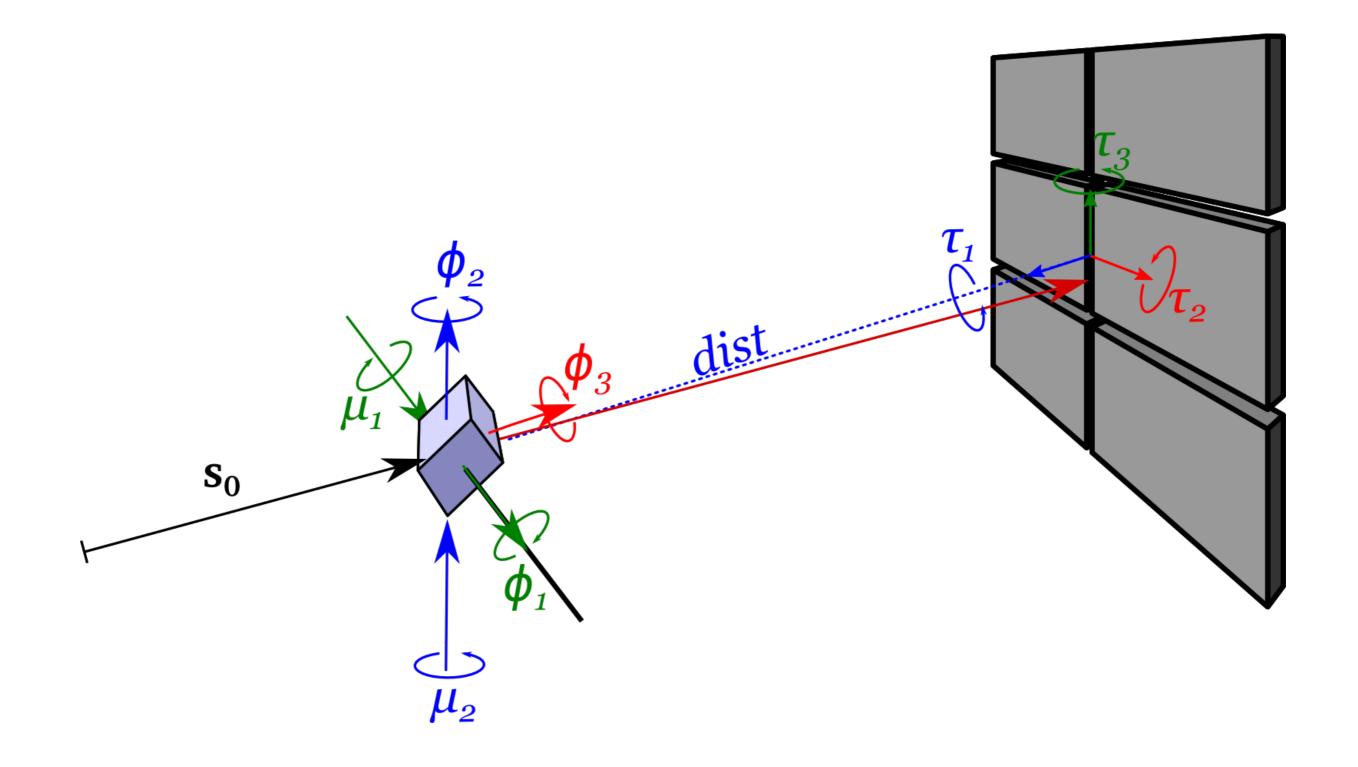
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#### SOLUTION PICKING

Solution Metric fit rmsd min/max cc #spots lattice

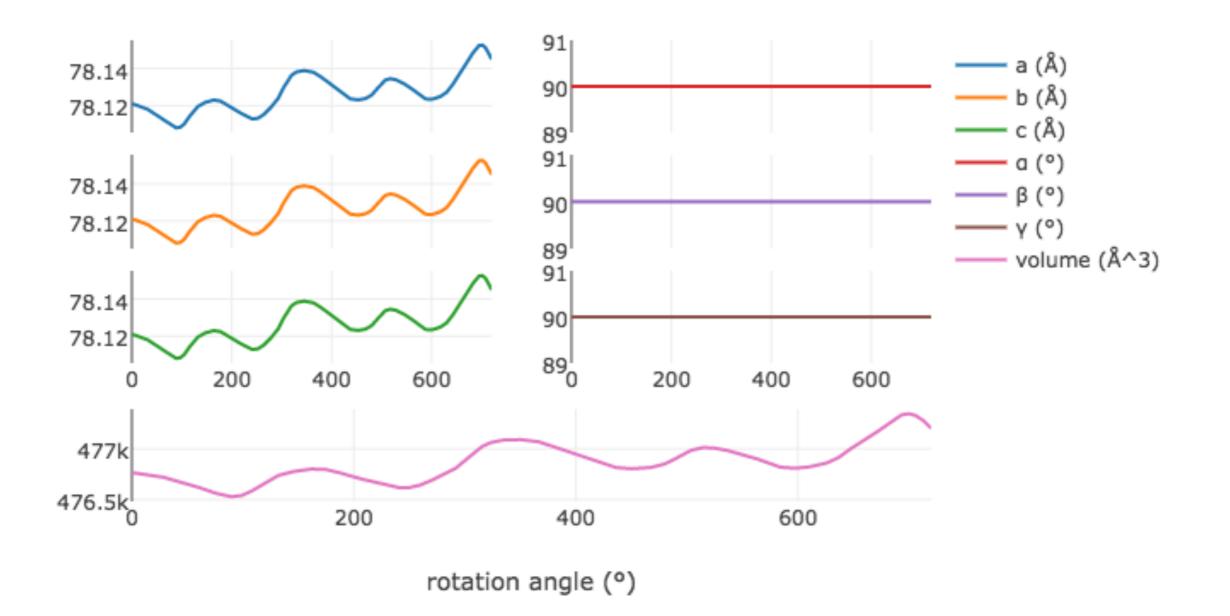
9 8 7 6 5 4 3 2	1.1465 0.655 0.4 1.1465 0.665 0.4 1.1465 0.540 0.4 1.0310 0.544 0.4 1.0311 0.392 0.4 1.0311 0.417 0.4 0.0165 0.056 0.4 0.0000 0.055	487/0.650 18000 487/0.487 18000 493/0.493 18000 650/0.884 18000 716/0.716 18000	oF mI mI oI mI mI	79,27 68,75 65,34 64,98 64,98 68,51 68,52 78,58 67,96 64,76 6
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#### REFINEMENT



#### REFINEMENT

Scan-varying cell parameters



#### INTEGRATION

#### 3.4. Intensity estimation

If an expected intensity distribution  $\{p_i | i \in D_0\}$  of the observed profile is given in a domain  $D_0$ , the reflection intensity *I* can be estimated as

$$I = \frac{\sum_{i \in D} (c_i - b_i) p_i / v_i}{\sum_{i \in D} p_i^2 / v_i},$$

which minimizes the function

$$\psi(I) = \sum_{i \in D} (c_i - I \cdot p_i - b_i)^2 / v_i, \quad \sum_{i \in D_0} p_i = 1.$$

 $b_i, c_i, v_i \ (i \in D)$  are the background, contents and variance of pixels observed in a subdomain  $D \subseteq D_0$  of the expected distribution. The background  $b_i$  underneath a diffraction spot is often assumed to be a constant which is estimated from the neighbourhood around the reflection.

#### /\*\*

```
* Evaluate the next intensity iteration.
 * @ returns The estimate of the intensity
 */
vec2<double>
estimate_intensity(const af::const_ref<FloatType, af::c_grid<3> > &p,
                   const af::const_ref<bool, af::c_grid<3> > &m,
                   const af::const_ref<FloatType, af::c_grid<3> > &c,
                   const af::const_ref<FloatType, af::c_grid<3> > &b,
                   double I) const {
  double sum1 = 0.0;
  double sum2 = 0.0;
  double sumv = 0.0;
 for (std::size_t i = 0; i < p.size(); ++i) {</pre>
    if (m[i]) {
      double v = std::abs(b[i]) + std::abs(I * p[i]);
      sumv += v;
      if (v > 0) {
        sum1 += (c[i] - b[i]) * p[i] / v;
        sum2 += p[i] * p[i] / v;
      }
    }
  }
  return vec2<double>(sum2 != 0 ? sum1 / sum2 : 0.0, sumv);
```

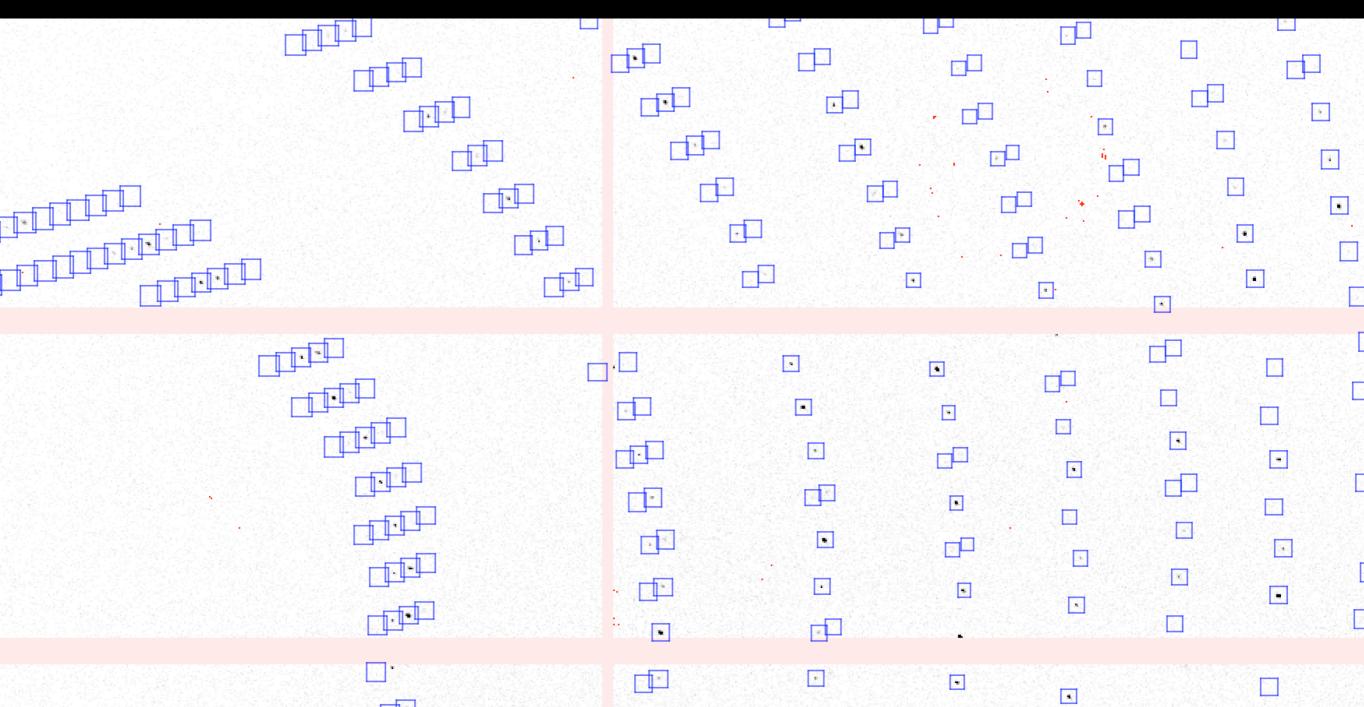
#### REFLECTION PROFILES

#### Full scan i.e. all images

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	4	2		1	(	6		8	1	0	1	2	

Profile for reflection at position x derived from average of strong reflections in block with centre nearest x

#### INTEGRATION



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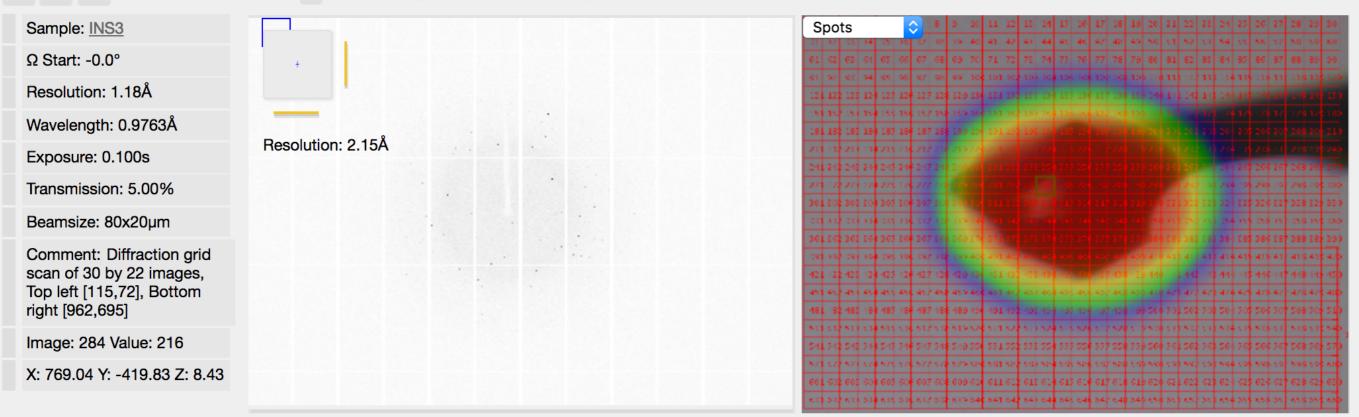
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RASTER / GRID SCAN

### TYPICAL RASTER SCAN - 660 IMAGES



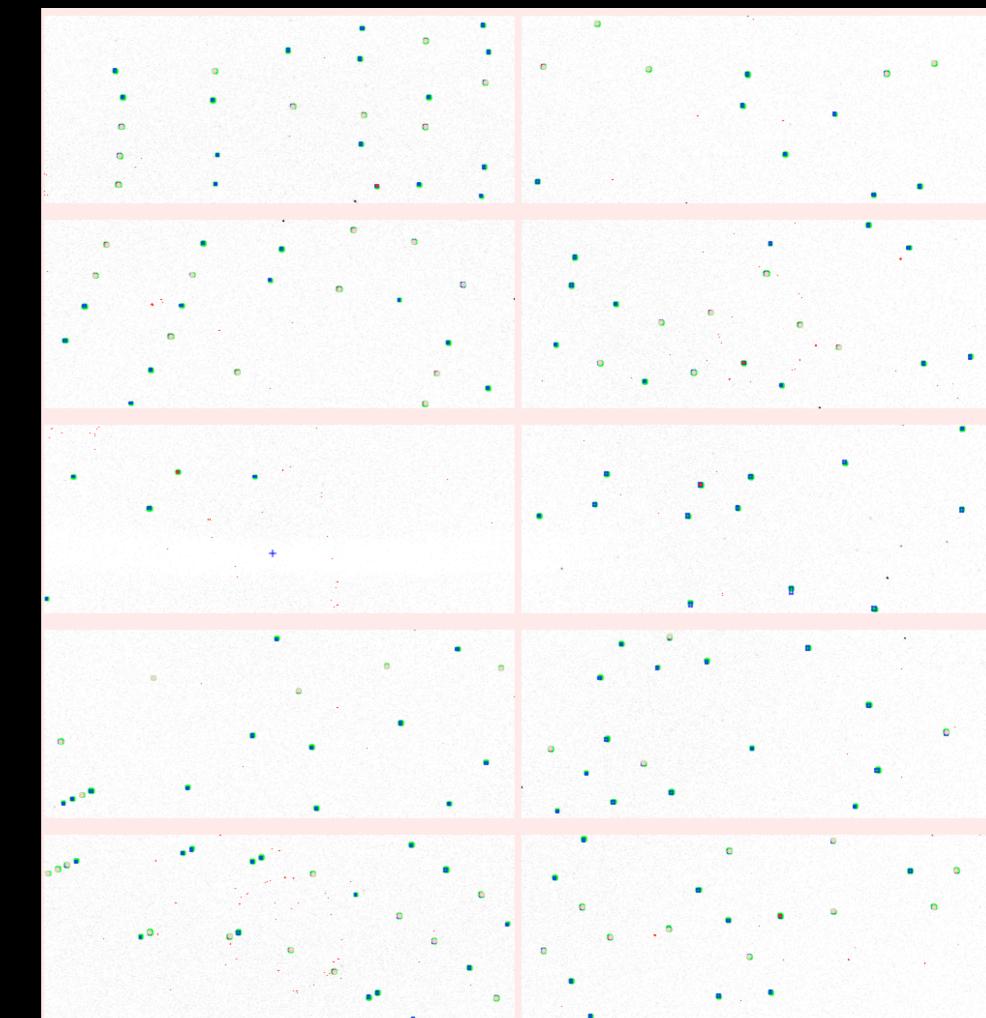
#### TIMING (SPOT FINDING)

Example set from Martin Savko @ Soleil: 750 frames, Eiger 9M, raster scan - data in ramdisk

- 50s from CBF on 20-core machine 1.3 frm / core / s
- 60s from HDF5 on 20-core machine 1.6 frm / core / s

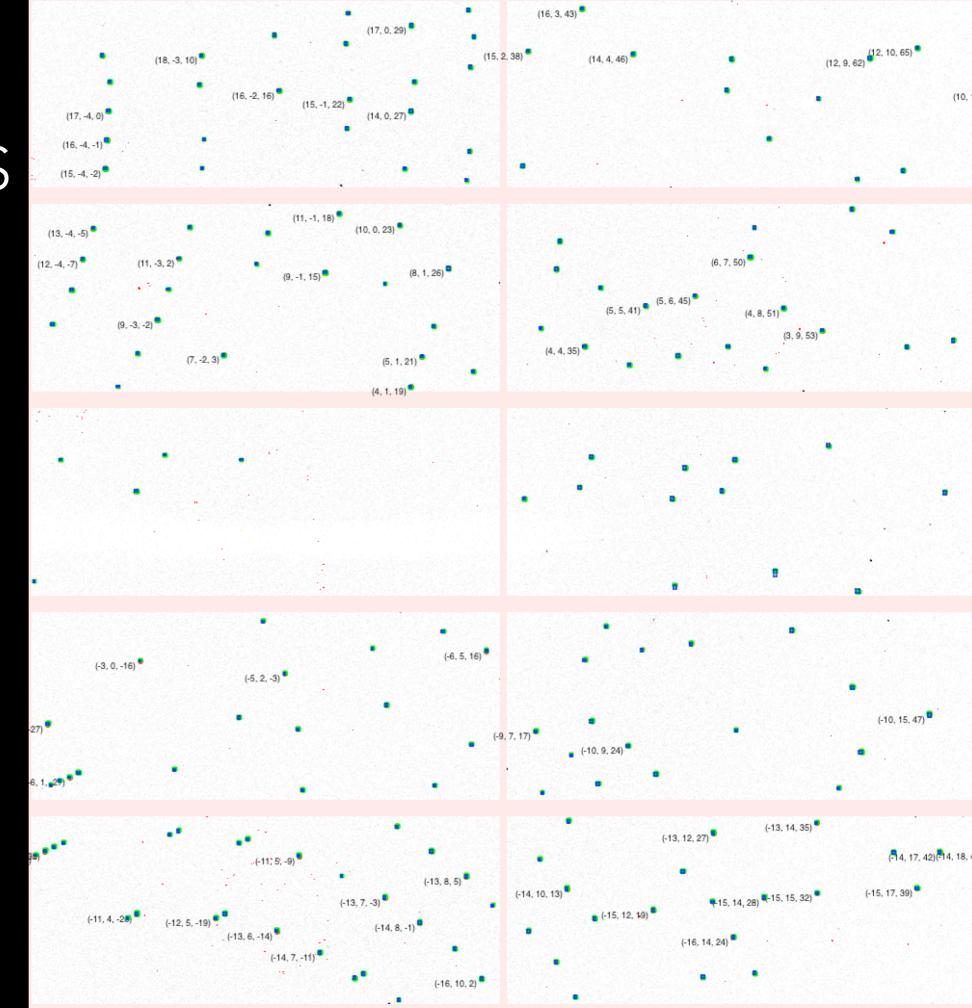
### RASTER METRICS

- #spots
- resolution
- shape
- I/sig(I)
- #lattices



### VMXI ANALYSIS

- #spots
- #lattices
- unit cell
- resolution
- • •



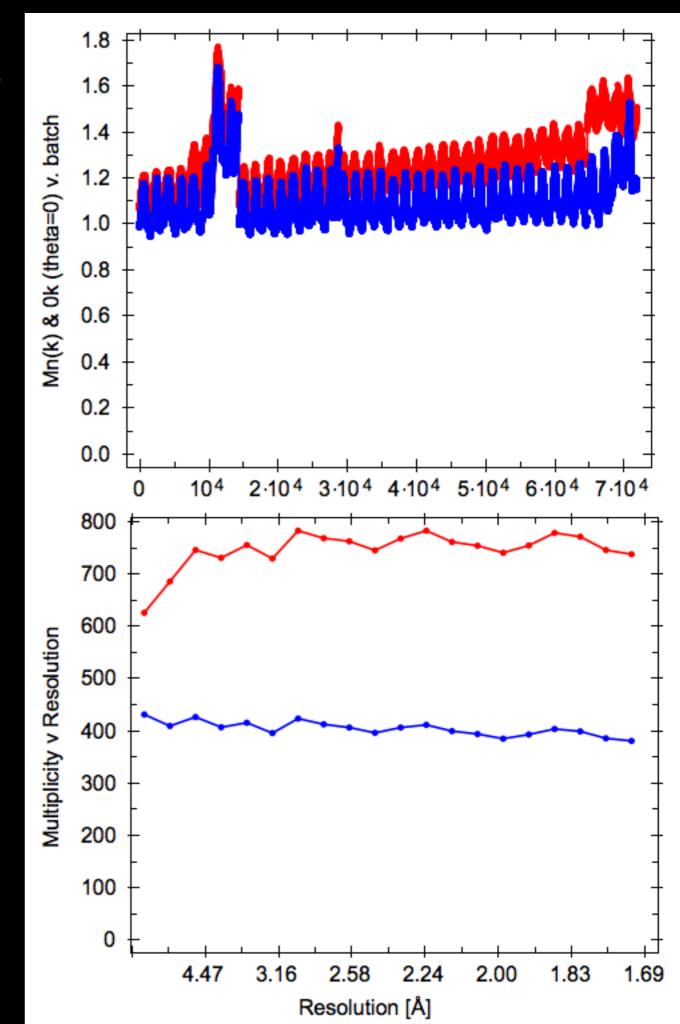
#### BENEFITS AND CHALLENGES

- Much greater computational cost spot finding ~ 1s, indexing ~ 10s, ... :-(
- Problem is embarrassingly parallel never need to bring the data together :-)
- May converge on synchrotron serial crystallography :-
- To provide useful feedback to user may require more advanced analytics :-(

# ROTATION DATA PROCESSING

#### HIGH MULTIPLICITY LOW DOSE

- Rational mode of data collection
- Take "standard" collection
- Record 10 x as many frames at 0.1 x dose / frame
- Post mortem decide where to stop experiment



#### BENEFITS AND CHALLENGES

- Always confident of getting complete data set :-)
- Making excellent use of low noise / photon counting detector :-)
- Avoid principle problem of MX collection :-)
- Have massive #frames :-(
- Sparse data compress well :-)
- Can apply parallelism i.e. integrate every run separately :-)

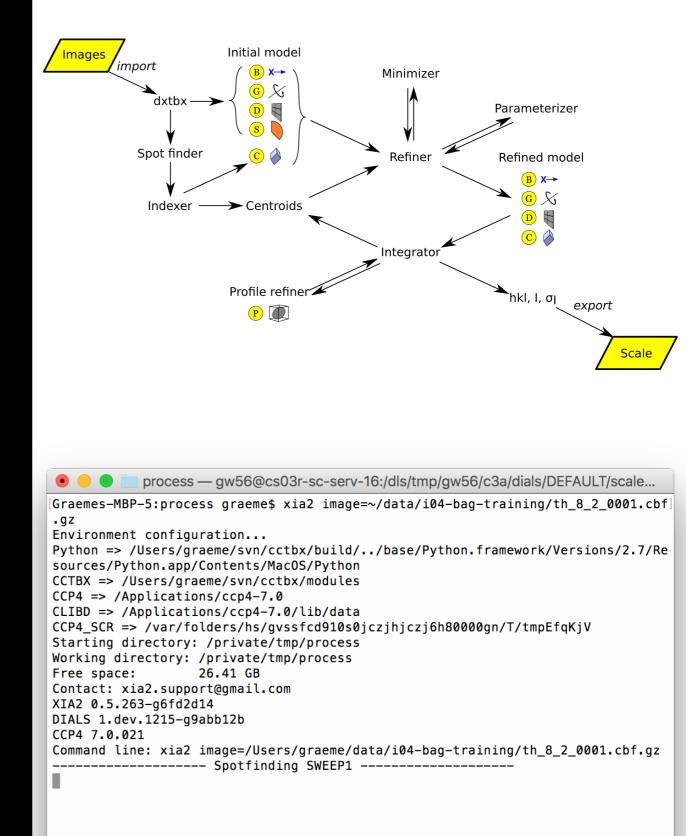
#### BIGGEST CHALLENGES

- Scaling :-(
- Deciding post-mortem where was best
- As soon as you have to look at every measurement time goes through the roof (aimless ~ 4 hours) :-(
- Find more parallel friendly algorithm XSCALE much quicker :-)
- Also have to be sure you are integrating carefully very small numbers of photons / spot likely :-(

# AUTOMATION

#### XIA2

- Embed indexing, integration, scaling
- Embed expertise on e.g. cluster usage
- Allows direct comparison with XDS (also inside xia2)
- Hides complexity of DIALS usage
- Scales well in high throughput environment





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- DIALS now used routinely at Diamond Light Source for automated data processing *via* xia2 will be in CCP4 7.0
- xia2 is the "friendly" DIALS user interface for synchrotron data, and is bundled with DIALS
- Tools developed using DIALS framework for image inspection, strategy evaluation on I19, detector metrology,



- Implement scaling new methods and new software
- Address errors critical for high multiplicity data
- Port to many-core architecture e.g. xeon phi
   address more complex serial crystallography challenges

#### ACKNOWLEDGEMENTS

- Development teams & users, CCTBX, Diamond staff,
   ...
- Funding EU, NIH, Wellcome, Diamond, CCP4, ...
- 21st century coding environment
- Users providing feedback and example data